

Description

The AP2301CI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -20V I_{D} = -2.3A$

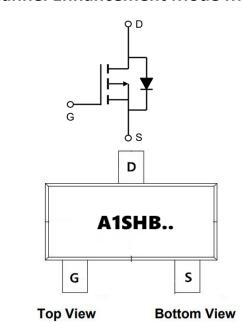
 $R_{DS(ON)} < 150 \text{m}\Omega$ @ V_{GS} =-4.5V (Type: 125m Ω)

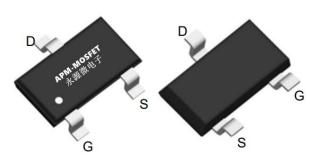
Application

Battery protection

Load switch

Uninterruptible power supply





Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|--------|---------|----------|
| AP2301CI | SOT23L | A1SHB | 3000 |

Absolute Maximum Ratings (T_c=25[°]Cunless otherwise noted)

| Symbol | Parameter | Rating | Units |
|--------------------------------------|--|------------|-------|
| V _{DS} | Drain-Source Voltage | -20 | V |
| V _G s | Gate-Source Voltage | ±12 | V |
| ID@T _A =25°C | Continuous Drain Current, V _{GS} @ -4.5V ¹ | -2.3 | А |
| I _D @T _A =70°C | Continuous Drain Current, V _{GS} @ -4.5V ¹ | -0.9 | А |
| I _{DM} | Pulsed Drain Current ² | -7.4 | А |
| P _D @T _A =25°C | Total Power Dissipation ³ | 1.1 | W |
| P _D @T _A =70°C | Total Power Dissipation ³ | 0.6 | W |
| Tstg | Storage Temperature Range | -55 to 150 | °C |
| TJ | Operating Junction Temperature Range | -55 to 150 | ° |
| R _θ JA | Thermal Resistance Junction-Ambient ¹ | 125 | °C/W |
| RθJC | Thermal resistance, junction-case | 32 | °C/W |





Electrical Characteristics (T_J=25°C, unless otherwise noted)

| Symbol | Parameter | Test Condition | Min. | Тур. | Max. | Units |
|----------------|--|---|------|------|------|-------|
| V(BR)DSS | Drain-Source Breakdown Voltage | V _{GS} =0V,I _D = -250μA | -20 | - | - | ٧ |
| IDSS | Zero Gate Voltage Drain Current | V _{DS} = -20V, V _{GS} = 0V, | - | - | -1 | μΑ |
| IGSS | Gate to Body Leakage Current | V _{DS} =0V, V _{GS} = ±12V | - | - | ±100 | nA |
| VGS(th) | Gate Threshold Voltage | V _{DS} = V _{GS} , I _D = -250µA | -0.4 | -0.7 | -1.0 | ٧ |
| RDS(on) | Static Drain-Source on-Resistance | V _{GS} =-4.5V, I _D =-2A | - | 125 | 150 | mΩ |
| | | V _{GS} =-2.5V, I _D =-1A | - | 145 | 180 | |
| Ciss | Input Capacitance | | - | 145 | - | pF |
| Coss | Output Capacitance | $V_{DS} = -10V, V_{GS} = 0V, f$ = 1.0MHz | - | 33 | - | pF |
| Crss | Reverse Transfer Capacitance | 1.0141112 | - | 23 | - | pF |
| Qg | Total Gate Charge | | - | 4.5 | - | nC |
| Qgs | Gate-Source Charge | $V_{DS} = -10V, I_{D} = -2A,$ $V_{GS} = -4.5V$ | - | 0.85 | - | nC |
| Qgd | Gate-Drain("Miller") Charge | | - | 1.4 | - | nC |
| td(on) | Turn-on Delay Time | | - | 6 | - | ns |
| tr | Turn-on Rise Time | $V_{DD} = -10V$, $R_L = 5\Omega$, | - | 30 | - | ns |
| td(off) | Turn-off Delay Time | $R_{GEN}=3\Omega, V_{GS}=-4.5V,$ | - | 45 | - | ns |
| t _f | Turn-off Fall Time | | - | 46 | - | ns |
| IS | Maximum Continuous Drain to Source Diode Forward Current | | - | - | -2.3 | Α |
| ISM | Maximum Pulsed Drain to Source Diode Forward Current | | - | - | -8 | Α |
| VSD | Drain to Source Diode Forward Voltage | V _{GS} = 0V, I _S = -2A | - | - | -1.2 | ٧ |

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2 、The data tested by pulsed , pulse width \triangle 300us , duty cycle \triangle 2%
- $3\ ^{\circ}$ The power dissipation is limited by 150 $^{\circ}\!\!\!\!\!\mathrm{C}$ junction temperature
- $4\sqrt{1}$ The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

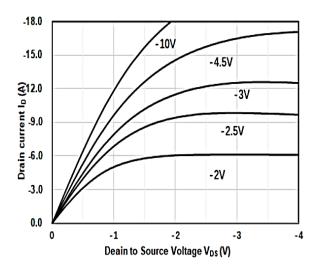


Figure1: Output Characteristics

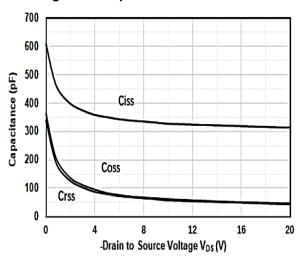


Figure 3: Capacitance Characteristics

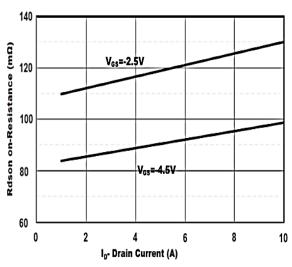


Figure 5: Drain-Source on Resistance

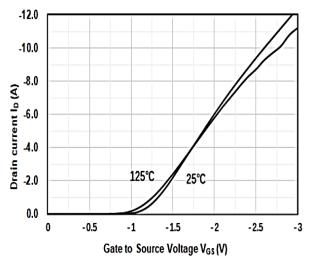


Figure 2: Typical Transfer Characteristics

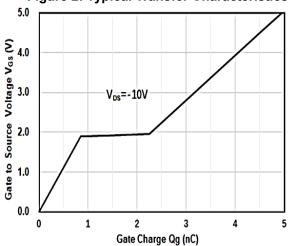


Figure 4: Gate Charge

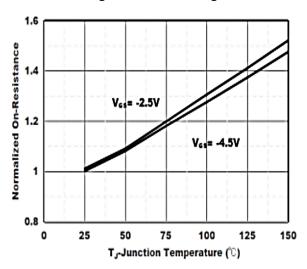
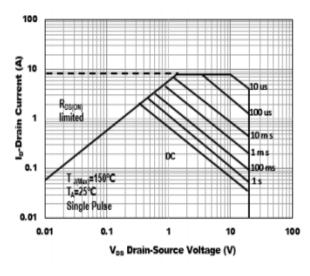


Figure 6: Drain-Source on Resistance







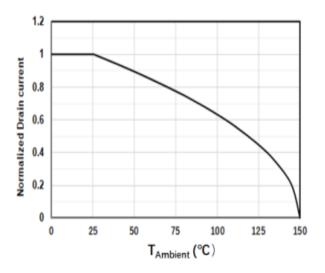


Figure 7: Safe Operation Area

Figure 8: Drain Current vs Ambient temperature

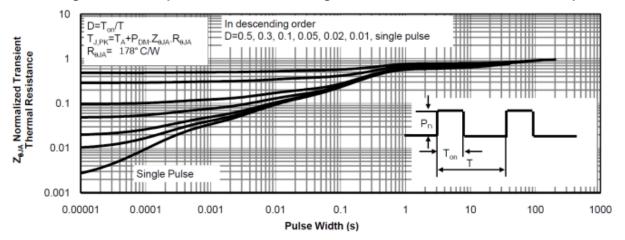
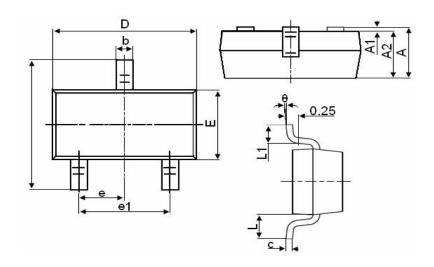


Figure 9: Normalized Maximum Transient Thermal Impedance



Package Mechanical Data-SOT23-XC-Single



| Currente e l | Dimensions in Millimeters | | |
|--------------|---------------------------|-------|--|
| Symbol | MIN. | MAX. | |
| Α | 0.900 | 1.150 | |
| A1 | 0.000 | 0.100 | |
| A2 | 0.900 | 1.050 | |
| b | 0.300 | 0.500 | |
| С | 0.080 | 0.150 | |
| D | 2.800 | 3.000 | |
| Е | 1.200 | 1.400 | |
| E1 | 2.250 | 2.550 | |
| е | 0.950TYP | | |
| e1 | 1.800 | 2.000 | |
| L | 0.550REF | | |
| L1 | 0.300 | 0.500 | |
| θ | 0° | 8° | |



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| Edition | Date | Change |
|---------|-----------|-----------------|
| REV1.0 | 2021/4/31 | Initial release |

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